

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Akiharu MIYANAGA et al. Art Unit : 2818
Serial No. : 10/667,899 Examiner : David Vu
Filed : September 23, 2003 Conf. No. : 8644
Title : SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE SAME

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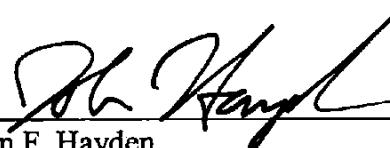
INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form.

Copies of any of the listed U.S. patents can be provided upon request.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,



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Date: 2/23/07

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Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-254003	Application No. 10/667,899
Information Disclosure Statement by Applicant <small>(Use several sheets if necessary)</small> <small>(37 CFR §1.98(b))</small>		Applicant Akiharu MIYANAGA et al.		
		Filing Date September 23, 2003	Group Art Unit 2818	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,251,733	06/26/2001	YAMAZAKI			04/07/2000
	AB	6,420,759	07/16/2002	YAMAZAKI et al.			12/28/2000
	AC	6,583,474	06/24/2003	YAMAZAKI et al.			06/28/2002
	AD	6,617,647	09/09/2003	YAMAZAKI			03/16/2001
	AE	6,653,687	11/25/2003	YAMAZAKI			08/08/1997
	AF	6,686,623	02/03/2004	YAMAZAKI			11/16/1998
	AG	6,690,075	02/10/2004	YAMAZAKI			06/04/2001
	AH	6,693,299	02/17/2004	YAMAZAKI et al.			07/13/1998
	AI	6,703,671	03/09/2004	YAMAZAKI et al.			07/28/1999
	AJ	6,724,037	04/20/2004	YAMAZAKI et al.			07/20/2001
	AK	6,867,085	03/15/2005	YAMAZAKI et al.			12/13/2000
	AL	6,885,059	04/26/2005	YAMAZAKI et al.			12/03/2003

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AR	
	AS	
	AT	
	AU	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	